## FCC ID:2AIIF09969PG

## Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)]  $[\sqrt{f(GHZ)}] \le 3.0$  for 1-g SAR and  $\le 7.5$  for 10-g extremity SAR, where:

- f(GHZ) is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

## BR+EDR:

Antenna Type: PCB Antenna Antenna Gain: -0.58 dBi

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Modulation	Channel Freq. (GHz)	Conduct ed power (dBm)	Conducte d power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculatio n	1g SAR Exclusion threshold	SAR test exclusion	
GFSK	2.402	-5.01	0.316	-6±1	-5.0	0.316	<5	0.09802	3.00	YES	
	2.441	-6.42	0.228	-6±1	-5.0	0.316	<5	0.09881	3.00	YES	
	2.480	-5.34	0.292	-6±1	-5.0	0.316	<5	0.09960	3.00	YES	
π/4- DQPSK	2.402	-4.38	0.365	-5±1	-4.0	0.398	<5	0.12340	3.00	YES	
	2.441	-5.8	0.263	-5±1	-4.0	0.398	<5	0.12440	3.00	YES	
	2.480	-4.63	0.344	-5±1	-4.0	0.398	<5	0.12539	3.00	YES	
8DPSK	2.402	-4.06	0.393	-5±1	-4.0	0.398	<5	0.12340	3.00	YES	
	2.441	-5.51	0.281	-5±1	-4.0	0.398	<5	0.12440	3.00	YES	
	2.480	-4.29	0.372	-5±1	-4.0	0.398	<5	0.12539	3.00	YES	

Conclusion:

Signature:

For the max result: 0.12539≤ 3.0 for 1-g SAR, No SAR is required.

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